
**Identification cards — Test
methods —**

Part 3:
**Integrated circuit cards with contacts
and related interface devices**

Cartes d'identification — Méthodes d'essai —

*Partie 3: Cartes à circuit(s) intégré(s) à contacts et dispositifs
d'interface assimilés*





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ISO copyright office
CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Fax: +41 22 749 09 47
Email: copyright@iso.org
Website: www.iso.org

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